Smart Octal Low-Side Switch
Features

Product Summary

- Protection
  - Overload, short circuit
  - Overtemperature
  - Overvoltage
- Low Quiescent Current< 10µA
- 16 bit SPI (for Daisychain)
- Direct Parallel Control of Four Channels
- PWM input (demux)
- Parallel Inputs High or Low Active Programmable
- Programmable functions
  - Boolean operation
  - Overload behavior
  - Overtemperature behavior
  - Switching time
- General Fault Flag
- Digital Ports Compatible to 5V and 3,3 V Micro Controllers
- **E**lectro**s**tatic **D**ischarge (ESD) Protection
- Full reverse current capability without latch up
- Green Product (RoHS compliant)
- AEC qualified

Supply voltage	V_S	4.5 – 5.5	V
Drain source clamping voltage	$V_{DS(AZ)max}$	60	V
On resistance	R_{ON}	0.8	Ω

Power PG-DSO 36-47

### Application
- µC-compatible 8-channel low-side switch
- Switch for Automotive and Industrial Applications
- Solenoids, Relays and Resistive Loads

General description
The TLE 7230 R is an Octal Low-Side Switch in Smart Power Technology (SPT) with a **S**erial **P**eripheral **I**nterface (SPI) and eight open drain DMOS output stages. It is protected by embedded protection functions and designed for automotive and industrial applications. The output stages are controlled via an SPI Interface. Additionally, four channels can be controlled in parallel for PWM applications. These features make the TLE 7230 R particularly suitable for engine management and body systems.

Detailed Block Diagram

V3.4   **GND**   Page   1   2009-07-15
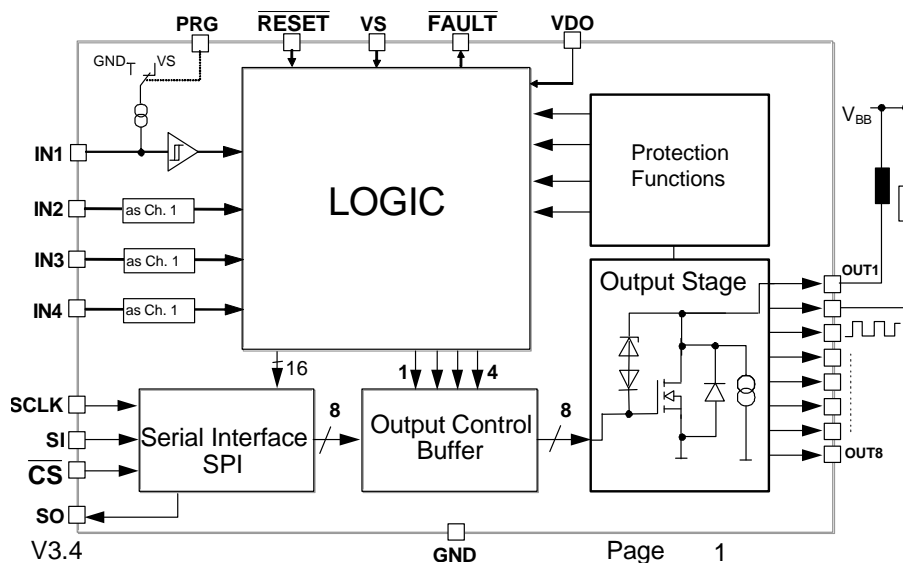
Power SO 36 package

Pin Description

Pin	Symbol	Function
1	GND	Ground
2	NC	not connected
3	NC	not connected
4	OUT1	Output Channel 1
5	OUT2	Output Channel 2
6	IN1	Input Channel 1
7	IN2	Input Channel 2
8	VS	Supply Voltage
9	Reset	Reset
10	CS	Chip Select
11	PRG	Program
12	IN3	Input Channel 3
13	IN4	Input Channel 4
14	OUT3	Output Channel 3
15	OUT4	Output Channel 4
16	NC	not connected
17	NC	not connected
18	GND	Ground
19	GND	Ground
20	NC	not connected
21	NC	not connected
22	OUT5	Output Channel 5
23	OUT6	Output Channel 6
24	NC	not connected
25	VDO	Supply for digital Outputs
26	Fault	General Fault Flag
27	SO	Serial Data Output
28	SCLK	Serial Clock
29	SI	Serial Data Input
30	NC	not connected
31	NC	not connected
32	OUT7	Output Channel 7
33	OUT8	Output Channel 8
34	NC	not connected
35	NC	not connected
36	GND	Ground

Pin Configuration (Top view)

1	GND	GND	36
2	NC	NC	35
3	NC	NC	34
4	Out1	Out8	33
5	Out2	Out7	32
6	IN1	NC	31
7	IN2	NC	30
8	VS	SI	29
9	Reset	SCLK	28
10	CS	SO	27
11	PRG	Fault	26
12	IN3	VDO	25
13	IN4	NC	24
14	Out3	Out6	23
15	Out4	Out5	22
16	NC	NC	21
17	NC	NC	20
18	GND	GND	19

Power- PG-DSO-36

Heat Slug internally connected to ground pins

Maximum Ratings for $T_j = -40°C$ to $150°C$

Parameter	Symbol	Values	Unit
Supply Voltage	V_S, V_{VDO}	-0.3 ... + 6	V
Continuous Drain Source Voltage (OUT1...OUT8)	V_{DS}	48	V
Input Voltage, All Inputs and Data Lines	V_{IN}	- 0.3 ... + 6	V
Operating Temperature Range	T_j	- 40 ... + 150	°C
Storage Temperature Range	T_{stg}	- 55 ... + 150	
Output Current per Channel (see el. characteristics)	$I_{D(lim)}$	$I_{D(lim)min}$	A
Reverse current per channel	I_R	- $I_{D(lim)min}$	A
Output Clamping Energy per channel (single pulse, triangular shape, individual switch off) $I_D = 0.3$ A, $T_{J(start)} = 150°C$ $I_D = 0.4$ A, $T_{J(start)} = 85°C$	E_{AS}	50 65	mJ
Output Clamping Energy per channel (repetitive pulses, triangular shape) $I_D = 0.25$ A, $T_{J(aver.)} = 150°C$, repetitive ($1 \cdot 10^6$ cycles)	E_{AR}	15	mJ
Maximum Battery Voltage for full short circuit protection (single pulse)[4] OVL = 0 OVL = 1	$V_{BAT(SC)}$	20 28	V
Electrostatic Discharge Voltage (Human Body Model) HBM according to EIA/JESD 22-A114 Output 1-8 Pins All other Pins	V_{ESD} V_{ESD}	2000 2000	V V
DIN Humidity Category, DIN 40 040		E	
IEC Climatic Category, DIN IEC 68-1		40/150/56	

Thermal Characteristics

Parameter	Symbol	Values		Unit
		min	max	
Thermal Resistance, Junction – Case (all channels active, 0.3W power dissipation each channel) (only one channel active, 0.5W power dissipation)	R_{thJC}	-- --	2.6 12	K/W

Electrical Characteristics

Parameter and Conditions		Symbol	Values			Unit
V_S = 4.5 to 5.5 V ; V_{VDO} = 3.0 to 5.5V; T_j = - 40 °C to + 150 °C ; Reset = H (unless otherwise specified)			min	typ	max	

1. Power Supply, Reset

Supply Voltage[1]		V_S	4.5	--	5.5	V
Supply Voltage Digital Output		V_{VDO}	3.0		5.5	V
Supply Current		I_S	--	3	5	mA
Supply Current (reset mode)	Reset = L	$I_{S(reset)}$	--		10	µA
Minimum Reset Duration		$t_{Reset,min}$	10	--	--	µs

2. Power Outputs

ON Resistance V_S = 5 V; I_D = 500 mA	T_J = 25°C [2]	$R_{DS(ON)}$	--	0.8	1	Ω
	T_J = 150°C		--	--	1.7	
Output Clamping Voltage	Output OFF	$V_{DS(AZ)}$	48	--	60	V
Current Limit		$I_{D(lim)}$	1		2	A
Output Leakage Current	V_{Reset} = L T_j =125°C ; V_{bb}=13.5V	$I_{D(lkg)}$	--	--	2	µA
Turn-On Time	SLE = 0	t_{ON}	--		15	µs
I_D = 0.5 A, resistive load	SLE = 1				60	
Turn-Off Time	SLE = 0	t_{OFF}	--		15	µs
I_D = 0.5 A, resistive load	SLE = 1				60	

3. Digital Inputs

Input Low Voltage		V_{INL}	- 0.3	--	1.0	V
Input High Voltage		V_{INH}	2.0	--	--	V
Input Voltage Hysteresis		V_{INHys}		100		mV
Input Pull Down/Up Current (IN1 ... IN4)		$I_{IN(1..4)}$	20	50	100	µA
PRG, Reset Pull Up Current		$I_{IN(PRG,Res)}$	20	50	100	µA
Input Pull Down Current (SI, SCLK)		$I_{IN(SI,SCLK)}$	10	20	50	µA
Input Pull Up Current (CS)		$I_{IN(CS)}$	10	20	50	µA

4. Digital Outputs (SO, Fault)

SO High State Output Voltage	I_{SOH} = 2 mA	V_{SOH}				V
	V_{VDO} = 5V		V_{VDO}–0.4	--	--	
	V_{VDO} = 3V		V_{VDO}–0.6			
SO Low State Output Voltage	I_{SOL} = 2.5 mA	V_{SOL}	--	--	0.4	V
Output Tristate Leakage Current, $\overline{CS}$ = H, 0 ≤ V_{SO} ≤ V_S		I_{SOlkg}	-10	0	10	µA
Fault Output Low Voltage	I_{FAULT} = 1.6 mA	V_{FAULTL}	--	--	0.4	V

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[1] For V_S < 4.5V the power stages are switched according the input signals and data bits or are definitely switched off. The undervoltage reset becomes active at V_S = 3V (typ. value) and is specified by design. Not subject to production test.

Electrical Characteristics cont.

Parameter and Conditions	Symbol	Values			Unit
V_S = 4.5 to 5.5 V; V_{VDO} = 3.0 to 5.5V; T_j = - 40 °C to + 150 °C ; Reset = H (unless otherwise specified)		min	typ	max	

5. Diagnostic Functions

Parameter and Conditions	Symbol	min	typ	max	Unit
Open Load Detection Voltage	$V_{DS(OL)}$	V_S -2.5	V_S -2	V_S -1.3	V
Output Pull Down Current	$I_{PD(OL)}$	50	90	150	µA
Fault Delay Time	$t_{d(fault)}$	50	100	200	µs
Overload switch off delay time	$T_{d(off)}$	10		50	µs
Short to Ground Detection Voltage	$V_{DS(SHG)}$	V_S -3.6	V_S -3.0	V_S -2.6	V
Short to Ground Detection Current	I_{SHG}	-50	-100	-150	µA
Overload Threshold Current	$I_{D(OVL) 1...8}$	1		2	A
Overtemperature Shutdown Threshold[2,4]	$T_{th(sd)}$	170	--	200	°C
Hysteresis[2]	T_{hys}	--	10	--	K

6. SPI-Timing (for V_{VDO} = 4.5V to 5.5V)

Parameter and Conditions	Symbol	min	typ	max	Unit
Serial Clock Frequency (depending on SO load)	f_{SCK}	DC	--	5	MHz
Serial Clock Period (1/fclk)	$t_{p(SCK)}$	200	--	--	ns
Serial Clock High Time	t_{SCKH}	50	--	--	ns
Serial Clock Low Time	t_{SCKL}	50	--	--	ns
Enable Lead Time (falling edge of CS to rising edge of CLK)	t_{lead}	250	--	--	ns
Enable Lag Time (falling edge of CLK to rising edge ofCS)	t_{lag}	250	---	--	ns
Data Setup Time (required time SI to falling of CLK)	t_{SU}	20	--	--	ns
Data Hold Time (falling edge of CLK to SI)	t_H	20	--	--	ns
Disable Time[2]	t_{DIS}	--	--	150	ns
Transfer Delay Time[3] (CS high time between two accesses)	t_{dt}	200	--	--	ns
Data Valid Time (for V_{VDO} = 4.5V to 5.5V) C_L = 50 pF[2] C_L = 100 pF[2] C_L = 220 pF[2]	t_{valid}	-- -- --		100 120 150	ns
Data Valid Time (for V_{VDO} = 3.0V to 3.6V) C_L = 50 pF[2] C_L = 100 pF[2] C_L = 220 pF[2]	t_{valid}	-- -- --		100 140 240	ns

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[2] This parameter is not subject to production test. Specified by design.
[3] This time is necessary between two write accesses. To get the correct diagnostic information, the transfer delay time has to be extended to the maximum fault delay time $t_{d(fault)max}$ = 200µs.

Functional Description

The TLE 7230 R is an octal low-side power switch with a serial peripheral interface (SPI) for control and diagnostic feedback of the 8 power DMOS switches. The power transistors are protected[4] against overload (current limitation), overtemperature and overvoltage (by active zener clamping). The diagnostic logic recognizes a fault condition which can be read out via the serial diagnostic output (SO).

Output Stage Control: Parallel Control or SPI Control
The Output stages can be controlled by parallel Inputs or by SPI commands. The IC can be programmed via SPI to switch the outputs according to the corresponding SPI command bit or to a combination of SPI bit and parallel input signal. The Boolean logic combination of parallel and serial signal is programmable by SPI to logic "AND" or "OR". The respective SPI data bits are active high and the parallel Inputs are active high or low according to the PRG pin (see pin description).

Boolean operation:
The logic combination of the parallel and the serial input signal can be configured by an SPI command for each of the 8 channels individually. Logic "AND" or logic "OR" is possible.

parallel in	serial in	Output "OR"	Output "AND"
off	off	off	off
off	on	on	off
on	off	on	off
on	on	on	on

Map able parallel input (IN 4):
The parallel input 4 (IN4) can be defined via SPI command as parallel input for one or more power outputs. Depending on the Input Map Register this input can be used to control one up to eight of the parallel outputs. Default operation: IN4 is the parallel input for channel 4.

Signal logic channel 1 to 3   Signal logic channel 4 to 8
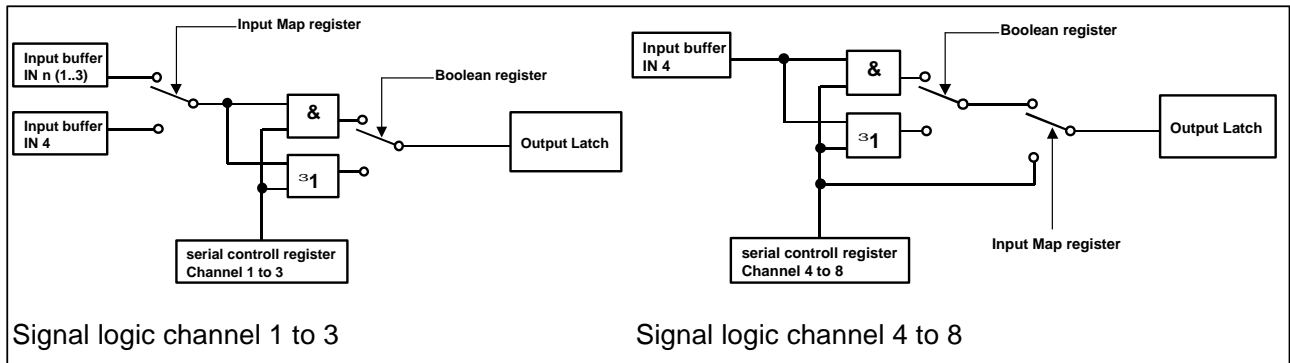
Switching speed / Slew rate:
The switching speed / slew rate of each individual channel can be configured by SPI for slow or fast switching speed (max. 15µs or 60µs).

Overtemperature Behavior:
Each channel has an overtemperature sensor and is individually protected against overtemperature. As soon as an overtemperature event occurs, the channel is immediately turned off and the overtemperature information is reported by diagnosis. In this case, there are two different behaviors of the affected channel that can be selected by SPI (for all channels individually).

- **Auto restart:** as long as the input signal of the channel remains on (e.g. parallel input high) the channel turns automatically on again after cooling down.
- **Latching**: In the event of an overtemperature shutdown, the channel stays off until the overtemperature latch is reset by a new L→H transition of the input signal.

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[4] The integrated protection functions help to prevent damage to the device under fault conditions and may not be used in normal operation or permanently.

Note: The overtemperature sensors of the output channels are only active if the channel is turned on.

Low Quiescent Current Mode (Sleep Mode) :
By applying a low signal at the Reset Pin, the device can be set to sleep mode. In this mode, all outputs are turned off, diagnosis and biasing are disabled, the diagnosis and the on/off register are reset and the current consumption is drastically reduced (<10µA). Once the reset signal returns to high, all outputs except for those controlled by parallel inputs remain off.

Overload Protection:
The IC can be programmed to react in different ways to overload.
- **Only Current limit:** The IC actively limits the current to the specified current limit value. If the current limitation is active for longer than the fault filtering time, a fault is reported and stored in the Fault register. Unless the channel reaches the overtemperature shutdown threshold, the channel is not shutdown.
- **Current limit + shutdown:** The IC actively limits the current to the specified current limit value. If this current limit is active for more than the specified Overload switch off delay time the affected channel is turned off and the fault is reported and stored in the fault register. To turn on the channel again this overload latch must be reset with a L→ H transition of the input signal (parallel /SPI depending on the programmed operation).

Pin description:

OUTPUT 1 to 8 – Drain pins of the 8 channels. Output pins to connect to loads.

GND – Ground pins.

IN 1 to 3 – Parallel Input Pins of the channels 1 to 3

IN 4 – Mapable parallel Input Pin. Can be assigned to different outputs by SPI command. Default Output is OUT4

PRG - Program pin.   PRG = High (V_S):   Parallel inputs 1 to 4 are high active
   PRG = Low (GND): Parallel inputs 1 to 4 are low active.
If the parallel input pins are not connected (independent of high or low activity) it is guaranteed that the channels 1 to 4 are switched OFF.
PRG pin itself is internally pulled up when not connected.

Reset - If the reset pin is in a logic low state, it clears the SPI shift register and switches all outputs OFF. An internal pull-up structure is provided on chip.

Fault - There is a general fault pin (open drain) which shows a high to low transition as soon as an error occurs at any one of the eight channels. This fault indication can be used to generate a µC interrupt. Therefore a 'diagnosis' interrupt routine need only be called after this fault indication. This saves processor time compared to a cyclic reading of the SO information.

VDO – Supply pin of the Signal Output (SO) pin of the SPI interface . This pin can be used to vary the high-state output voltage of the SO pin.

Vs – Logic supply pin. This pin is used to supply the integrated circuitry.

CS – Chip Select of the **S**erial **P**eripheral **I**nterface

SO – Signal Output of the **S**erial **P**eripheral **I**nterface

SI – Signal Input of the **S**erial **P**eripheral **I**nterface. The pin has an internal pull down structure.

**SCLK** – Clock Input of the **S**erial **P**eripheral **I**nterface. The pin has an internal pull down structure

SPI

The SPI is a **S**erial **P**eripheral **I**nterface with 4 digital pins and a 16 bit shift register. The SPI is used to configure and program the device, turn on and off channels and to read detailed diagnostic information.
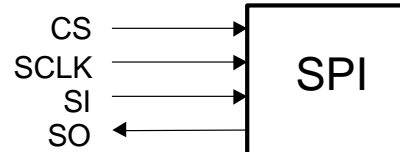
SPI Signal Description:

CS - Chip Select. The system microcontroller selects the TLE 7230 R by means of the CS pin. Whenever the pin is in a logic low state, data can be exchanged between the µC and TLE 7230 R.
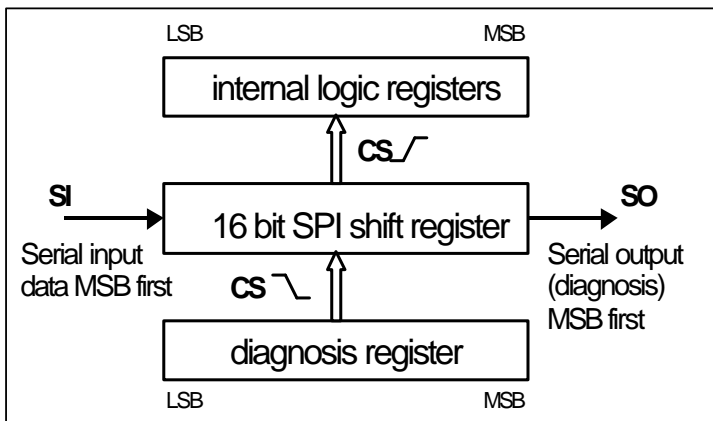
CS = H: Any signals at the SCLK and SI pins are ignored and SO is forced into a high impedance state.

CS = H→L:
- diagnostic information is transferred from the diagnosis register into the SPI shift register. (in sleep mode no transfer of diagnostic information)
- serial input data can be clocked into the SPI shift register from then on
- SO changes from high impedance state to logic high or low state corresponding to the SO bits

CS = L: SPI functions as a shift register. With each clock signal at the SCLK pin the state of the SI is read into the SPI shift-register (falling clock edge) and one diagnosis bit is written out of SO (rising edge).

CS = L→H:
- transfer of SI bits from SPI shift register into the internal logic registers sent command is valid
- reset of diagnosis register if sent command is valid

To avoid any false clocking the serial clock input pin SCLK should be logic low state during high to low transition of CS. The SPI of the TLE 7230 R has an integrated modulo 8 counter. If the number of clock signals is not an integer multiple of 8 the SPI will not accept the data in the shift register and the fault register will not be reset.

SCLK - Serial Clock. The serial clock pin clocks the internal SPI shift register of the TLE 7230 R. The serial input (SI) accepts data into the input SPI shift register on the falling edge while the serial output (SO) shifts diagnostic information out of the SPI shift register on the rising edge of serial clock. It is essential that the SCLK pin is in a logic low state whenever chip select (CS) makes any transition.

SI - Serial Input. Serial data bits are shifted in at this pin, the most significant bit (MSB) first. SI information is read in on the falling edge. Input data is latched in the SPI shift register and then transferred to the internal registers of the logic.

The input data consist of 16 bit, made up of x control bits and y data bits. The control bits are used address the desired SPI register and the data bits are used to program in user-specified settings.

SO - Serial Output. Diagnostic data bits are shifted out serially at this pin, the most significant bit (MSB) first. SO is in a high impedance state until the CS pin goes to a logic low state. New diagnostic data will appear at the SO pin following the rising edge.

SPI Control and Commands:

MSB	14	13	12	11	10	9	8	7	6	5	4	3	2	1	LSB
SI: CMD		x	x	x		ADDR					DATA				

SO standard diagnosis

Ch 8		Ch 7		Ch 6		Ch 5		Ch 4		Ch 3		Ch 2		Ch 1	

SO after read command in previous frame

SO: 0	1	0	0	0		ADDR					DATA				

CMD   Command:

0 0 : Diagnosis Only :
Reads out the diagnosis register. This command has no other influence on the device.

0 1 : Read register :
With the next SO data frame the content of the addressed register will be sent.

1 0 : Reset Registers:
Resets back all internal registers. Logic registers to default and Fault registers to no error.

1 1 : Write register :
The data of the SI word will be written to the addressed register.

No valid Commands:
If the first 8 bit of the SI word contains an invalid command, it will not result in any re-action by the TLE 7230 R (register value change, switching channels, ...). Additionally an L→H of Chip Select (CS) will not reset the diagnosis register.

ADDR   Address:
Pointer to register for read and write command

DATA   Data:
Data written to or read from register selected by address ADDR

Ch x   Standard diagnosis for channel x:
For details see "SPI Diagnostics"

Register Description:

Name	Nr.	7	6	5	4	3	2	1	0	ADDR	default
MAP	1	Ch8	Ch7	Ch6	Ch5	Ch4	Ch3	Ch2	Ch1	0 0 1	08$_H$
BOL	2	Ch8	Ch7	Ch6	Ch5	Ch4	Ch3	Ch2	Ch1	0 1 0	00$_H$
OVL	3	Ch8	Ch7	Ch6	Ch5	Ch4	Ch3	Ch2	Ch1	0 1 1	00$_H$
OVT	4	Ch8	Ch7	Ch6	Ch5	Ch4	Ch3	Ch2	Ch1	1 0 0	00$_H$
SLE	5	Ch8	Ch7	Ch6	Ch5	Ch4	Ch3	Ch2	Ch1	1 0 1	00$_H$
STA	6	OUT8	OUT7	OUT6	OUT5	OUT4	OUT3	OUT2	OUT1	1 1 0	00$_H$
CTL	7	Ch8	Ch7	Ch6	Ch5	Ch4	Ch3	Ch2	Ch1	1 1 1	00$_H$

Input Mapping Register (MAP**)**
Defines to which outputs the input IN4 is assigned (can be one up to all)
        0.. No connection to IN4
        1.. Output can be controlled with IN4 pin

Boolean operation Register (BOL**)**
The logic operation for serial and parallel control signal can be individually defined for each channel.
        0.. Logic "OR"
        1.. Logic "AND"

Overload Behavior Register (OVL**)**
The overload behavior of individual channels can be defined.
        0.. Current limit without shutdown of the channel
        1.. Current limit with latching overload shutdown of the channel

Overtemperature Behavior Register (OVT**)**
The overtemperature behavior of individual channels can be defined
        0.. Auto restart after cooling down
        1.. Latching shutdown on overtemperature

Switching Speed / Slew Rate Register (SLE**)**
The switching speed of individual channels can be defined.
        0.. fast (10µs)
        1.. slow (50µs)

Output State Register (STA**)**
Reads back the state of the output (this register is read-only)
        0: DMOS off
        1: DMOS on

Serial Output Control Register (CTL**)**
Sets the serial control bits for switching of output stages.
        0: Output off
        1: Output on

SPI Diagnostics:

As soon as a fault occurs for longer than the fault filtering time, the fault information is latched into the diagnosis register (the Fault pin will also change from high to low state). A new error on the same channel will overwrite the old error report. Serial data out pin (SO) is in high impedance state when CS is high. If CS receives a LOW signal, all diagnosis bits can be shifted out serially. If the sent command is valid the rising edge of CS will reset all diagnosis registers and restart the fault filtering time. In case of an invalid command the device will ignore the data bits and the diagnosis register will not be reset at the rising CS edge.

Figure 1: Two bits per channel diagnostic feedback
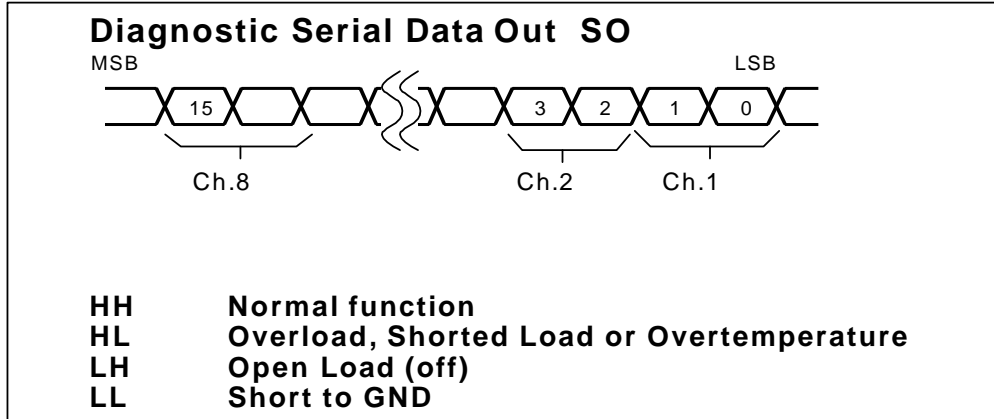
For Full Diagnosis there are two dedicated diagnostic bits per channel, as shown in Figure 1.
Normal function: The bit combination **HH** indicates that there is no fault condition, i.e. normal function.

Overload, Shorted Load or Overtemperature: HL is set if the current limitation becomes active, i.e. in the event of an overload or short to supply event. Additionally, this bit combination is set in the event of overtemperature of the corresponding channel.

Open load: LH is set if an open load is detected (in off state of the channel)

Short to GND: LL is set if a short to ground condition is detected (in off state)
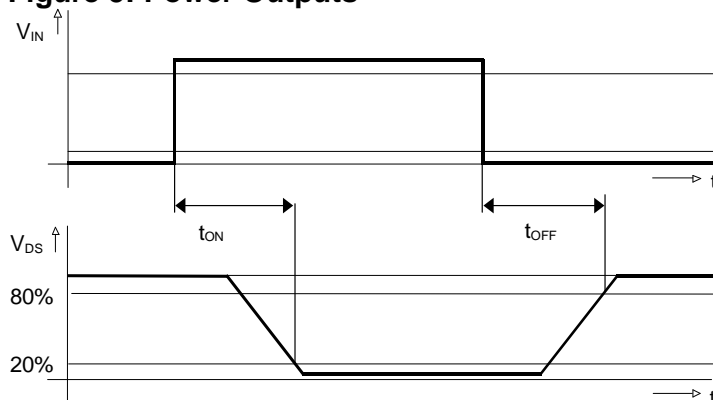
Timing Figures

Figure 5: Power Outputs
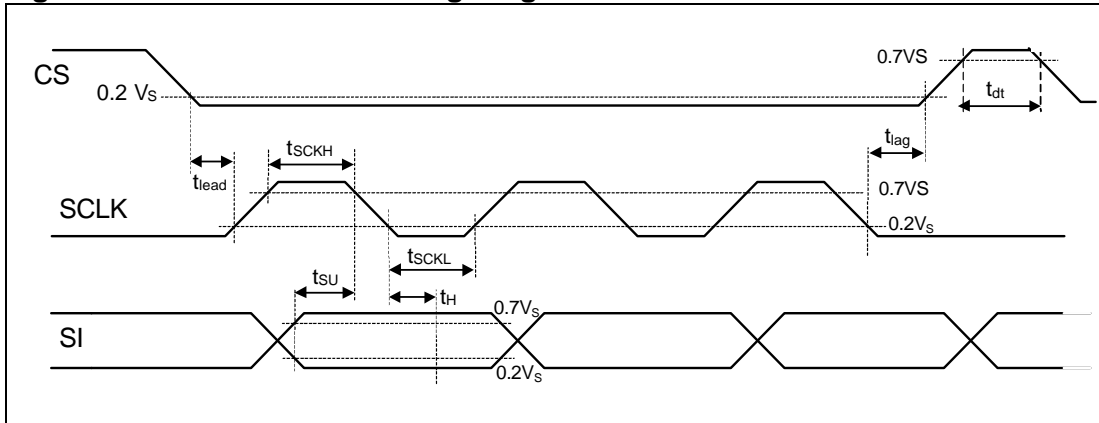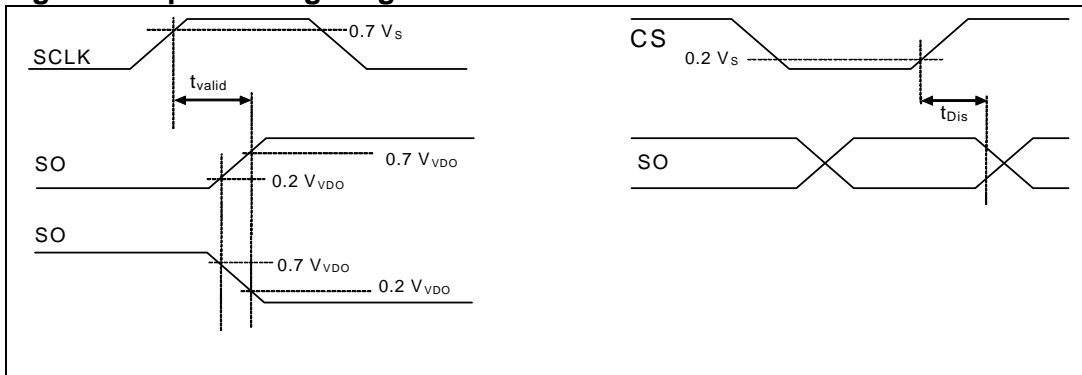
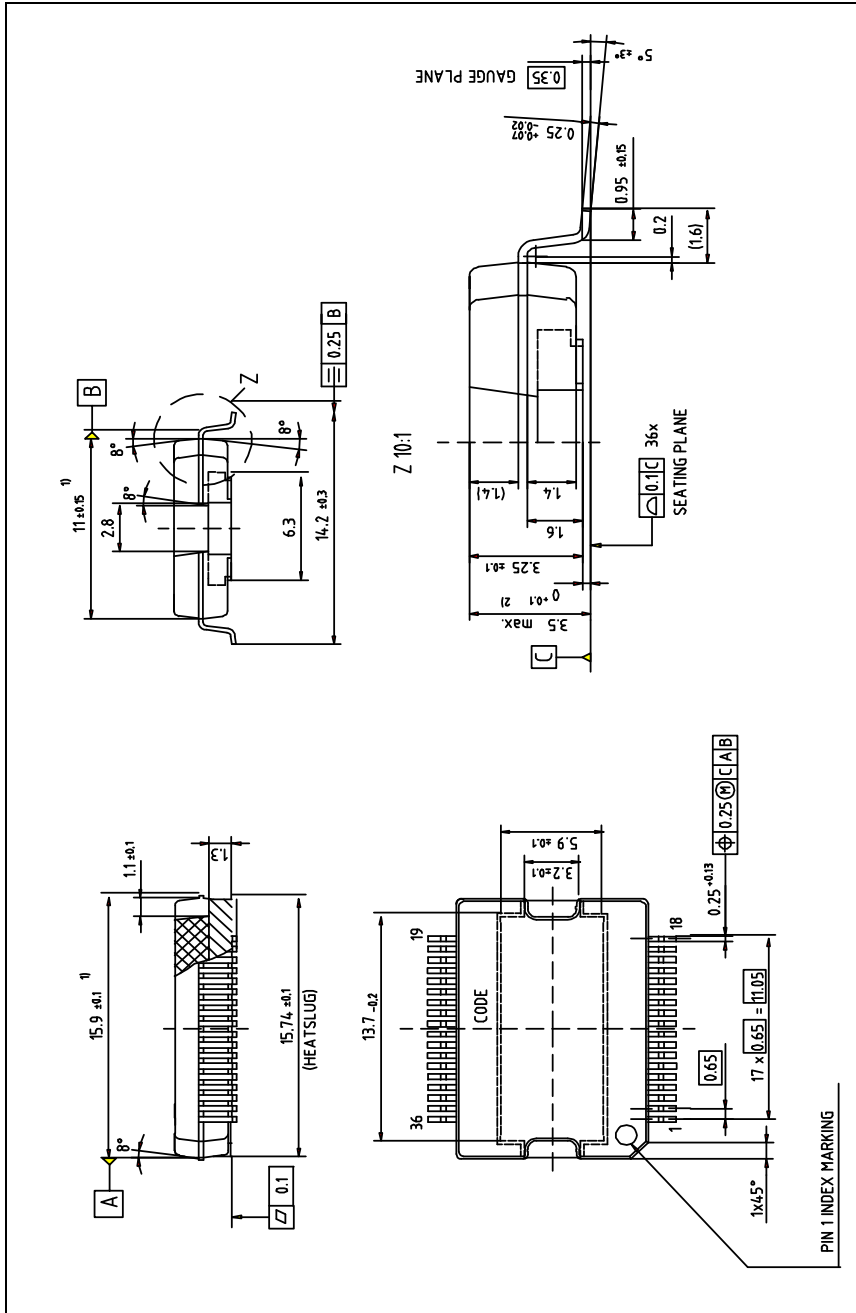**Figure 6: Serial Interface Timing Diagram**

Figure 7: Input Timing Diagram

SO Valid Time Waveforms   **Enable and Disable Time Waveforms**

Revision History

Version	Date	Changes
V3.4 ->V3.3	2009-07-15	Short to Ground Detection Voltage min limit changed from V_S -3.4 to V_S -3.6
V3.3 -> V3.2	2008-07-22	Version Change : changed Package naming only
V3.1 -> V3.2	2007-06-11	Version Change
	2007-06-11	Revision History cleaned – only "final" data sheet related contents

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